

RESISTIVITY REFERENCE WAFER



- NRW series Resistivity Reference Wafers use wafers with neutron irradiation, and has excellent stability.
- Napson’s four-probe resistivity measurement system is calibrated by standard wafers (NIST, VLSI) and conforms to the standards stipulated by the following Compliance Standards;
 - ✓ **SEMI Standards:** SEMI-MF43-99, SEMI-MF374-02, SEMI-MF84-02, SEMI-MF1529-02
 - ✓ **Japan Industrial Standards:** JIS-H-0602-1995
- **Wafer Specifications:**
 - ✓ Material: Silicon
 - ✓ Production Method: FZ
 - ✓ Wafer finish frontside/backside: Lapped
 - ✓ Doping: N-type (Phosphorous)
 - ✓ Wafer size: Φ 100mm (4")
 - ✓ Resistivity Accuracy: 3%, ϕ 5mm spot from sample center

MEASURE RANGE				
P/N	RESISTIVITY (Ω .cm)	THICKNESS (μ m)	CALCULATED SHEET RESISTANCE (Ω /sq)	WAFER ORIENTAION
NRW-6-16	16.00 \pm 2.00	650.00 \pm 25.00	Approx. 250	(1-1-1) \pm 1°
NRW-7-42	41.50 \pm 3.50	650.00 \pm 25.00	Approx. 650	(1-1-1) \pm 1°
NRW-8-52	52.00 \pm 2.00	650.00 \pm 25.00	Approx. 800	(1-0-0) \pm 1°
NRW-2-110	110.00 \pm 11.00	580.00 \pm 10.00	Approx. 2000	(1-1-1) \pm 1°
NRW-3-200	200.00 \pm 12.00	675.00 \pm 25.00	Approx. 3000	(1-1-1) \pm 1°
NRW-4-330	330.00 \pm 25.00	675.00 \pm 25.00	Approx. 5000	(1-1-1) \pm 1°
NRW-5-550	550.00 \pm 50.00	450.00 \pm 25.00	Approx. 12000	(1-1-1) \pm 1°